FINAL

Am27C2048

2 Megabit (131,072 x 16-Bit) CMOS EPROM

DISTINCTIVE CHARACTERISTICS

- Fast access time
 - 55 ns maximum access time
- Low power consumption
 - 100 μA maximum CMOS standby current
- JEDEC-approved pinout
 - Plug-in upgrade of 1 Mbit EPROM
 - 40-pin DIP/PDIP
 - 44-pin PLCC
- Single +5 V power supply

- ±10% power supply tolerance standard
- 100% Flashrite programming
 - Typical programming time of 16 seconds
- Latch-up protected to 100 mA from -1 V to V_{CC} + 1 V
- Versatile features for simple interfacing
 - Both CMOS and TTL input/output compatibility
 - Two line control functions
- High noise immunity

GENERAL DESCRIPTION

The Am27C2048 is a 2 Mbit, ultraviolet erasable programmable read-only memory. It is organized as 128K words by 16 bits per word, operates from a single +5 V supply, has a static standby mode, and features fast single address location programming. The Am27C2048 is ideal for use in 16-bit microprocessor systems. Products are available in windowed ceramic DIP packages as well as plastic one time programmable (OTP) PDIP and PLCC packages.

Typically, any byte can be accessed in less than 70 ns, allowing operation with high-performance microprocessors without any WAIT states. The Am27C2048 offers separate Output Enable (\overline{OE}) and Chip Enable (\overline{CE}) controls, thus eliminating bus contention in a multiple bus microprocessor system.

AMD's CMOS process technology provides high speed, low power, and high noise immunity. Typical power consumption is only 125 mW in active mode, and 100 μ W in standby mode.

All signals are TTL levels, including programming signals. Bit locations may be programmed singly, in blocks, or at random. The Am27C2048 supports AMD's Flashrite programming algorithm (100 μ s pulses) resulting in typical programming time of 16 seconds.

BLOCK DIAGRAM



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PRODUCT SELECTOR GUIDE

Family Part No.		Am27C2048					
Ordering Part No: $V_{CC} = 5.0 \text{ V} \pm 5\%$	-55						-255
$V_{CC}=5.0~V\pm10\%$	-55	-70	-90	-120	-150	-200	
Max Access Time (ns)	55	70	90	120	150	200	250
CE (E) Access (ns)	55	70	90	120	150	200	250
OE (G) Access (ns)	40	40	40	50	65	75	75

CONNECTION DIAGRAMS

Top View

DIP								
			L.					
V _{PP}	1 -	40	V _{cc}					
CE (Ē)	2	39	PMG (P)					
DQ15	3	38	NC					
DQ14	4	37	_ A15					
DQ13	5	36	_ A14					
DQ12	6	35	_ A13					
DQ11	7	34	_ A12					
DQ10	8	33	_ A11					
DQ9	9	32	_ A10					
DQ8	10	31	_ A9					
V _{SS}	11	30] ∨ _{ss}					
DQ7	12	29	_ A8					
DQ6	13	28] A7					
DQ5	14	27	_ A6					
DQ4	15	26	_ A5					
DQ3	16	25	_ A4					
DQ2	17	24] A3					
DQ1	18	23] A2					
DQ0	19	22] A1					
OE (G)	20	21] A0					



Notes:

1. JEDEC nomenclature is in parenthesis.

2. Don't use (DU) for PLCC.

PIN DESIGNATIONS

A0–A16	=	Address Inputs
\overline{CE} (\overline{E})	=	Chip Enable Input
DQ0-DQ15	=	Data Input/Outputs
\overline{OE} (\overline{G})	=	Output Enable Input
\overline{PGM} (\overline{P})	=	Program Enable Input
V _{CC}	=	V _{CC} Supply Voltage
V _{PP}	=	Program Voltage Input
V _{SS}	=	Ground

LOGIC SYMBOL



11407F-2

ORDERING INFORMATION

UV EPROM Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:



2 Megabit (131,072 x 16-Bit) CMOS UV EPROM

Valid C	Valid Combinations						
AM27C2048-55 V_{CC} = 5.0 V ± 5%	DC5, DC5B, DI5, DI5B						
AM27C2048-55 V _{CC} = 5.0 V ± 10%							
AM27C2048-70	DC, DCB, DI, DIB						
AM27C2048-90							
AM27C2048-120							
AM27C2048-150	DC, DCB, DE, DEB, DI, DIB						
AM27C2048-200							
AM27C2048-255 V_{CC} = 5.0 V ± 5%	DC, DCB, DI, DIB						

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations and to check on newly released combinations.

ORDERING INFORMATION

OTP EPROM Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of:



2 Megabit (131,072 x 16-Bit) CMOS OTP EPROM

Valid Combinations						
AM27C2048-55 V_{CC} = 5.0 V ± 5%	PC5, PI5, JC5, JI5					
AM27C2048-55 V _{CC} = 5.0 V ± 10%						
AM27C2048-70						
AM27C2048-90						
AM27C2048-120	PC, PI, JC, JI					
AM27C2048-150						
AM27C2048-200	-					
AM27C2048-255 V _{CC} = 5.0 V ± 5%						

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations and to check on newly released combinations.

FUNCTIONAL DESCRIPTION

Erasing the Am27C2048

In order to clear all locations of their programmed contents, it is necessary to expose the Am27C2048 to an ultraviolet light source. A dosage of 15 W seconds/cm² is required to completely erase an Am27C2048. This dosage can be obtained by exposure to an ultraviolet lamp—wavelength of 2537 Å—with intensity of 12,000 μ W/cm² for 15 to 20 minutes. The Am27C2048 should be directly under and about one inch from the source and all filters should be removed from the UV light source prior to erasure.

It is important to note that the Am27C2048, and similar devices, will erase with light sources having wavelengths shorter than 4000 Å. Although erasure times will be much longer than with UV sources at 2537 Å, nevertheless the exposure to fluorescent light and sunlight will eventually erase the Am27C2048 and exposure to them should be prevented to realize maximum system reliability. If used in such an environment, the package window should be covered by an opaque label or substance.

Programming the Am27C2048

Upon delivery, or after each erasure, the Am27C2048 has all 2,097,152 bits in the "ONE", or HIGH state. "ZEROs" are loaded into the Am27C2048 through the procedure of programming.

The programming mode is entered when 12.75 V \pm 0.25 V is applied to the V_PP pin, and \overline{CE} and \overline{PGM} are at V_{IL}.

For programming, the data to be programmed is applied 16 bits in parallel to the data pins.

The flowchart (Figure 2) shows AMD's Flashrite algorithm. The Flashrite algorithm reduces programming time by using 100 μ s programming pulse and by giving each address only as many pulses as are necessary in order to reliably program the data. After each pulse is applied to a given address, the data in that address is verified. If the data does not verify, additional pulses are given until it verifies or the maximum is reached. This process is repeated while sequencing through each address of the Am27C2048. This part of the algorithm is done at V_{CC} = 6.25 V to assure that each EPROM bit is programmed to a sufficiently high threshold voltage. After the final address is completed, the entire EPROM memory is verified at V_{CC} = V_{PP} = 5.25 V.

Please refer to Section 6 for programming flow chart and characteristics.

Program Inhibit

Programming of multiple Am27C2048s in parallel with different data is also easily accomplished. Except for \overline{CE} , all like inputs of the parallel Am27C2048 may be

common. A TTL low-level program pulse applied to an Am27C2048 \overline{CE} input with V_{PP} = 12.75 V ± 0.25 V and PGM LOW will program that Am27C2048. A high-level \overline{CE} input inhibits the other Am27C2048 devices from being programmed.

Program Verify

A verify should be performed on the programmed bits to determine that they were correctly programmed. The verify should be performed with \overline{OE} and \overline{CE} , at V_{IL}, \overline{PGM} at V_{IH}, and V_{PP} between 12.5 V and 13.0 V.

Auto Select Mode

The auto select mode allows the reading out of a binary code from an EPROM that will identify its manufacturer and type. This mode is intended for use by programming equipment for the purpose of automatically matching the device to be programmed with its corresponding programming algorithm. This mode is functional in the $25^{\circ}C \pm 5^{\circ}C$ ambient temperature range that is required when programming the Am27C2048.

To activate this mode, the programming equipment must force 12.0 V \pm 0.5 V on address line A9 of the Am27C2048. Two identifier bytes may then be sequenced from the device outputs by toggling address line A0 from V_{IL} to V_{IH}. All other address lines must be held at V_{IL} during auto select mode.

Byte 0 (A0 = V_{IL}) represents the manufacturer code, and Byte 1 (A0 = V_{IH}), the device identifier code. For the Am27C2048, these two identifier bytes are given in the Mode Select table. All identifiers for manufacturer and device codes will possess odd parity, with the MSB (DQ7) defined as the parity bit.

Read Mode

The Am27C2048 has two control functions, both of which must be logically satisfied in order to obtain data at the outputs. Chip Enable (\overline{CE}) is the power control and should be used for device selection. Output Enable (\overline{OE}) is the output control and should be used to gate data to the output pins, independent of device selection. Assuming that addresses are stable, address access time (t_{ACC}) is equal to the delay from \overline{CE} to output (t_{CE}). Data is available at the outputs t_{OE} after the falling edge of \overline{OE} , assuming that \overline{CE} has been LOW and addresses have been stable for at least $t_{ACC}-t_{OE}$.

Standby Mode

The Am27C2048 has a CMOS standby mode which reduces the maximum V_{CC} current to 100 μ A. It is placed in CMOS-standby when \overline{CE} is at $V_{CC}\pm0.3$ V. The Am27C2048 also has a TTL-standby mode which reduce the maximum V_{CC} current to 1.0 mA. It is placed in TTL-standby when \overline{CE} is at V_{IH} . When in standby mode, the outputs are in a high-impedance state, independent of the \overline{OE} input.

Output OR-Tieing

To accommodate multiple memory connections, a two-line control function is provided to allow for:

- Low memory power dissipation, and
- Assurance that output bus contention will not occur

It is recommended that \overline{CE} be decoded and used as the primary device-selecting function, while \overline{OE} be made a common connection to all devices in the array and connected to the READ line from the system control bus. This assures that all deselected memory devices are in their low-power standby mode and that the output pins are only active when data is desired from a particular memory device.

System Applications

During the switch between active and standby conditions, transient current peaks are produced on the rising and falling edges of Chip Enable. The magnitude of these transient current peaks is dependent on the output capacitance loading of the device. At a minimum, a 0.1 μ F ceramic capacitor (high frequency, low inherent inductance) should be used on each device between V_{CC} and V_{SS} to minimize transient effects. In addition, to overcome the voltage drop caused by the inductive effects of the printed circuit board traces on EPROM arrays, a 4.7 μ F bulk electrolytic capacitor should be used between V_{CC} and V_{SS} for each eight devices. The location of the capacitor should be close to where the power supply is connected to the array.

	Pins							
Mode		CE	ŌĒ	PGM	A0	A9	V _{PP}	Outputs
Read		V _{IL}	V _{IL}	Х	X	Х	X	D _{OUT}
Output Disat	ble	V _{IL}	V _{IH}	X	x	Х	X	High Z
Standby (TT	L)	V _{IH}	Х	Х	х	Х	Х	High Z
Standby (CM	1OS)	$V_{CC}\pm0.3V$	Х	Х	х	Х	Х	High Z
Program		V _{IL}	Х	V _{IL}	х	Х	V _{PP}	D _{IN}
Program Ver	ify	V _{IL}	V _{IL}	V _{IH}	X	Х	V _{PP}	D _{OUT}
Program Inh	ibit	V _{IH}	Х	Х	x	Х	V _{PP}	High Z
Auto Select	Manufacturer Code	V _{IL}	V _{IL}	х	VIL	V _H	х	01H
(Note 3)	Device Code	V _{IL}	V _{IL}	Х	V _{IH}	V _H	Х	98H

MODE SELECT TABLE

Notes:

1. $V_H = 12.0 V \pm 0.5 V.$

2. $X = Either V_{IH} or V_{IL}$.

3. $A1 - A8 = A10 - 16 = V_{IL}$.

4. See DC Programming Characteristics for V_{PP} voltage during programming.

ABSOLUTE MAXIMUM RATINGS

Storage Temperature
OTP Products
All Other Products65°C to +150°C
Ambient Temperature
with Power Applied55°C to +125°C
Voltage with Respect to V _{SS}
All pins except A9, V_{PP} , V_{CC} , –0.6 V to V_{CC} + 0.6 V
A9 and V_{PP} (Note 2)
V_{CC} (Note 1)
Notes:

- 1. Minimum DC voltage on input or I/O pins -0.5 V. During voltage transitions, the input may overshoot V_{SS} to -2.0 V for periods of up to 20 ns. Maximum DC voltage on input and I/O pins is $V_{CC} + 5$ V. During voltage transitions, input and I/O pins may overshoot to $V_{CC} + 2.0$ V for periods up to 20 ns.
- Minimum DC input voltage on A9 is –0.5 V. During voltage transitions, A9 and V_{PP} may overshoot V_{SS} to –2.0 V for periods of up to 20 ns. A9 and V_{PP} must not exceed+13.5 V at any time.

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure of the device to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices

Ambient Temperature (T_A) $0^{\circ}C$ to +70°C
Industrial (I) Devices
Ambient Temperature (T_A) 40°C to +85°C
Extended (E) Devices
Ambient Temperature (T_A) 55°C to +125°C
Supply Read Voltages
Voo for Am27C2048-55 255 +4 75 V to +5 25 V

 v_{CC} for Am27C2048 (All Others) . +4.75 V to +5.25 V V_{CC} for Am27C2048 (All Others) . +4.50 V to +5.50 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

DC CHARACTERISTICS over operating range unless otherwise specified (Notes 1, 2, and 4)

Parameter Symbol	Parameter Description	Test Conditio	Min	Max	Unit	
V _{OH}	Output HIGH Voltage	I _{OH} = -400 μ.	A	2.4		V
V _{OL}	Output LOW Voltage	I _{OL} = 2.1 mA	٨		0.45	V
V _{IH}	Input HIGH Voltage		2.0	V _{CC} + 0.5	V	
V _{IL}	Input LOW Voltage		-0.5	+0.8	V	
I _{LI}	Input Load Current	$V_{IN} = 0 V \text{ to } V_{CC}$	C/I Devices		1.0	μA
			E Devices		5.0	
I _{LO}	Output Leakage Current	V _{OUT} = 0 V to \	/cc		5.0	μA
I _{CC1}	V _{CC} Active Current	$CE = V_{IL}$,	C/I Devices		50	_
	(Note 3)	f = 5 MHz, I _{OUT} = 0 mA	E Devices		60	mA
I _{CC2}	V _{CC} TTL Standby Current	$\overline{CE} = V_{IH}$			1.0	mA
I _{CC3}	V _{CC} CMOS Standby Current	$\overline{\text{CE}} = \text{V}_{\text{CC}} \pm 0.3 \text{ V}$			100	μA
I _{PP1}	V _{PP} Supply Current (Read)	$\overline{\text{CE}} = \overline{\text{OE}} = \text{V}_{\text{IL}}, \text{V}_{\text{PP}} = \text{V}_{\text{CC}}$			100	μA

Notes:

1. V_{CC} must be applied simultaneously or before V_{PP} and removed simultaneously or after V_{PP}

2. **Caution**: The Am27C2048 must not be removed from (or inserted into) a socket when V_{CC} or V_{PP} is applied.

3. I_{CC} 1 is tested with $\overline{OE} = V_{IH}$ to simulate open outputs.

 Minimum DC Input Voltage is -0.5 V. During transitions, the inputs may overshoot to -2.0 V for periods less than 20 ns. Maximum DC Voltage on output pins is V_{CC} + 0.5 V, which may overshoot to V_{CC} + 2.0 V for periods less than 20 ns.



 V_{CC} = 5.5 V, T = 25°C

vs. Temperature $V_{\rm CC} = 5.5 V, f = 5 MHz$

CAPACITANCE

Parameter Parameter		CDV040		PD 040		PL 044			
Symbol	Description	Test Conditions	Тур	Max	Тур	Max	Тур	Max	Unit
C _{IN}	Input Capacitance	V _{IN} = 0	10	12	10	12	7	10	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0	12	15	12	15	12	14	pF

Notes:

1. This parameter is only sampled and not 100% tested.

2. $T_A = +25^{\circ}C, f = 1 MHz.$

AC CHARACTERISTICS

Parameter Symbols		Am27C2048										
JEDEC	Standard	Description	Test Se	Test Setup		-70	-90	-120	-150	-200	-255	Unit
t _{AVQV}	t _{ACC}	Address to Output Delay	CE, OE = V _{IL}	Max	55	70	90	120	150	200	250	ns
t _{ELQV}	t _{CE}	Chip Enable to Output Delay	$\overline{OE} = V_{IL}$	Max	55	70	90	120	150	200	250	ns
t _{GLQV}	t _{OE}	Output Enable to Output Delay	$\overline{CE} = V_{IL}$	Max	40	40	40	50	65	75	75	ns
t _{ehqz} t _{ghqz}	t _{DF} (Note 3)	Chip Enable to Output High Z or Output Enable to Output High Z to Output Float, Whichever Occurs First		Max	25	25	25	30	30	40	60	ns
t _{AXQX}	t _{OH}	Output Hold Time from Addresses, CE or OE, Whichever Occurs First		Min	0	0	0	0	0	0	0	ns

Notes:

1. Caution: Do not remove the Am27C2048 from (or insert it into) a socket or board that has V_{PP} or V_{CC} applied.

2. V_{CC} must be applied simultaneously or before V_{PP} and removed simultaneously or after V_{PP}

- 3. This parameter is sampled and not 100% tested.
- 4. Switching characteristics are over operating range, unless otherwise specified.
- 5. Test Conditions for Am27C2048-55:

Output Load: 1 TTL gate and $C_L = 30 \text{ pF}$ Input rise and fall times: 20 ns Input pulse levels: 0.0 V to 3.0 V Timing measurement reference level Inputs and Outputs: 1.5 V

Test Conditions for all others:

Output Load: 1 TTL gate and C_L = 100 pF Input rise and fall times: 20 ns Input pulse levels: 0.45 V to 2.4 V Timing measurement reference level Inputs and Outputs: 0.8 and 2.0 V

SWITCHING TEST CIRCUIT



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SWITCHING TEST WAVEFORM

Notes:





AC Testing for -55 devices: Inputs are driven at 3.0 V for a logic "1" and 0 V for a logic "0". Input pulse rise and fall times are ≤20 ns.

AC Testing (except for -55 devices): Inputs are driven at 2.4 V for a logic "1" and 0.45 V for a logic "0". Input pulse rise and fall times are ≤20 ns.

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KEY TO SWITCHING WAVEFORMS



SWITCHING WAVEFORMS



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REVISION SUMMARY FOR AM27C2048

Distinctive Characteristics:

The fastest speed grade available is now 55 ns.

Product Selector Guide:

Added 55 ns column.

Ordering Information, UV EPROM Products:

The 55 ns part number is now listed in the example. The nomenclature now has a method of clearly designating the voltage operating range and speed grade.

Ordering Information, OTP EPROM Products:

Changed the part number example from -70 to -55. The nomenclature now has a method of clearly designating the voltage operating range and speed grade.

Valid Combinations: Added the 55 ns speed grade to the table.

Operating Ranges:

Changed Supply Read Voltages listings to match those in the Product Selector Guide.

AC Characteristics:

Added column for 55 ns speed grade, rearranged notes, moved text from table title to Note 4, renamed table.

Switching Test Circuit:

Added 55 ns to the C_L note on 30 pF test condition.

Switching Test Waveform:

Added the 3 V test waveform.